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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>				Complete if Known	
				Application Number	10/555,729
				Filing Date	December 21, 2006
				First Named Inventor	Shuming Nie
				Group Art Unit	1641
				Examiner Name	Leon Yun Bon Lum
Attorney Docket Number				239659	
Client Reference No.				0215-US	
Sheet	1	of	1		

U.S. PATENT DOCUMENTS						
Examiner Initials	Doc. No.	U.S. Patent Document		Name of Patentee or Applicant	Date of Publication	Filing Date If Appropriate
		Application or Patent Number	Kind Code			
/L.Y.L./	AY	2003/0047816	A1	Dutta	Mar. 13, 2003	
/L.Y.L./	AZ	2003/0066998	A1	Lee	Apr. 10, 2003	

FOREIGN PATENT DOCUMENTS							
Examiner Initials	Doc. No.	Foreign Patent Document			Name of Patentee or Applicant	Date of Publication	Translation *
		Office	Application or Patent Number	Kind Code			

OTHER - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Doc. No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number (s), publisher, city and/or country where published.	Translation *
/L.Y.L./	BA	BAILEY et al., <i>J. Am. Chem. Soc.</i> , 125(23):7100-7106 (2003)	
/L.Y.L./	BB	GOLAN et al., <i>Adv. Materials VCH Verlagsgesellschaft</i> , 8(8):631-633 (1996)	
/L.Y.L./	BC	GURUSINGHE et al., <i>J. Phys. Chem.</i> , 112:12795-12800 (2008)	
/L.Y.L./	BD	ZHU et al., <i>Mat. Res. Soc. Symp. Proc.</i> , 607:291-296 (2000)	

Examiner Signature	/Leon Y. Lum/	Date Considered	10/22/2009
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* If the reference is not in English, then at least one of the following is provided: (a) an English translation in whole or in part or (b) a concise statement of relevance in the form of, for example, an English language counterpart, an English-language abstract, or an English-language version of the search report or action by a foreign patent office in a counterpart foreign application indicating the degree of relevance found by the foreign office.